

Product Summary

VDSS

RDS(on), typ

QG, typ

 $Q_{\text{RR, typ}}$

Schematic Symbol

650

120

21

26

V

mΩ

nC

nC

650V GaN Power Transistor (FET)

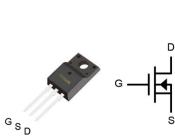
Features

- Easy to use, compatible with standard gate drivers
- Excellent Q_G x R_{DS(on)} figure of merit (FOM)
- Low QRR, no free-wheeling diode required
- Low switching loss
- RoHS compliant and Halogen-free

Applications

- High efficiency power supplies
- Telecom and datacom
- Automotive
- Servo motors

Packaging



Cascode Device Structure

S

Part Number	Package	Packaging	Base QTY
RX65T125FS2A	3 Lead TO-220F	Tube	50

Maximum ratings, at Tc=25 ℃, unless otherwise specified

Symbol	Parameter	Limit Value	Unit	
Continuous drain current @T _c =25°C			11.3	А
ID	I _D Continuous drain current @Tc=100℃		7	А
	Pulsed drain current @Tc=25℃ (pulse width: 10us)		80	А
Ідм	Pulsed drain current @T _C =150℃ (pul	58	А	
V _{DSS}	Drain to source voltage (T」 = -55℃ to	650	V	
VTDSS	Transient drain to source voltage ^a	800	V	
V _{GSS}	Gate to source voltage	±20	V	
PD	Maximum power dissipation @T _C =25℃		29	W
Tc		Case	-55 to 150	°C
٦J	Operating temperature	Junction	-55 to 150	°C
Ts	Storage temperature	-55 to 150	°C	
TCSOLD	Soldering peak temperature		260	°C



Thermal Resistance

Symbol	Parameter	Typical	Unit
Rοjc	Junction-to-case	4.3	℃/W
Roja	Junction-to-ambient ^b	50	℃/W

Notes:

- a. Off-state spike duty cycle < 0.01, spike duration < 2us
- Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm² copper area and 70μm thickness)



RX65T125FS2A

Electrical Parameters, at TJ=25 °C, unless otherwise specified

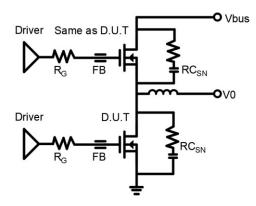
Symbol	Min	Тур	Max	Unit	Test Conditions	
Forward Chara	cteristics	I	I			
Vdss-max	650	-	-	V	V _{GS} =0V	
BV _{DSS}		1000		V	V _{GS} =0V, I _{DSS} =250μA	
V _{GS(th)}	3	4	5	V	V _{DS} =V _{GS} , I _D =500μA	
R _{DS(on)} ^c	-	120	150	mΩ	V _{GS} =8V, I _D =4A, T _J =25℃	
	-	240	-		V _{GS} =8V, I _D =4A, T _J =150℃	
Idss	-	5	20	μA	V _{DS} =700V, V _{GS} =0V, T _J =25℃	
IDSS	-	50	-	μA	V _{DS} =700V, V _{GS} =0V, T _J =150℃	
I _{GSS}	-	-	150	nA	V _{GS} =20V	
IGSS	-	-	-150	nA	V _{GS} =-20V	
Ciss	-	606	-	pF		
Coss	-	40	-	pF	V _{GS} =0V, V _{DS} =650V, f=1MHz	
Crss	-	3	-	pF		
C _{O(er)}	-	57	-	pF		
Co(tr)	-	109	-	pF	- V _{GS} =0V, V _{DS} =0 - 650V	
Q _G	-	21	-			
Q _{GS}	-	6.7	-	nC	V _{DS} =400V, V _{GS} =0 - 12V, I _D =10A	
Q _{GD}	-	5	-			
t _{D(on)}	-	44	-			
t _R	-	16	-			
t _{D(off)}	-	40	-	ns	V _{DS} =400V, V _{GS} =0 - 12V, I _D =10A, R _G =40 Ω	
t⊦	-	12	-			
Reverse Chara	cteristics					
	-	1.3	-	V	V _{GS} =0V, I _S =5A, T _J =25°C	
V_{SD}	-	1.9	-		V _{GS} =0V, I _S =10A, T _J =25°C	
	-	3	-		V _{GS} =0V, I _S =10A, T _J =150°C	
t _{RR}	-	16	-	ns		
Q _{RR}	-	26	-	nC	Is=10A, V _{GS} =0V, d _i /d _t =1000A/us, V _{DD} =400V	

Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations



Circuit Implementation



Recommended Single Ended Drive Circuit

Recommended gate drive: (0 V, 12 V) with $R_{G(tot)}$ = 34 Ω , where $R_{G(tot)}$ = R_{G} + R_{Driver}

Gate Ferrite Bead	Gate Resistance1	RC Snubber
(FB)	(R _G)	(RC _{SN})
MPZ1608S471ATA00	33 Ω	69 pF + 15 Ω

Notes:

- d. RCsn should be placed as close as possible to the drain pin
- e. The layout and wiring of the drive circuit should be as short as possible



Typical Characteristics, at Tc=25 °C, unless otherwise specified

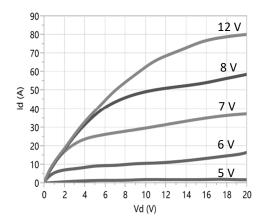
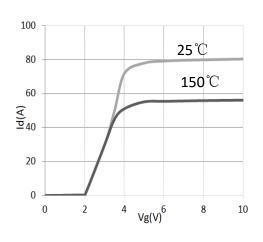
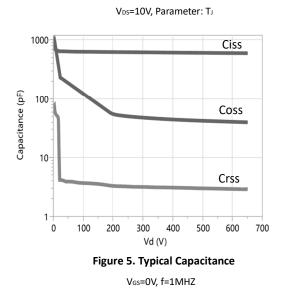


Figure 1. Typical Output Characteristics T_J=25°C







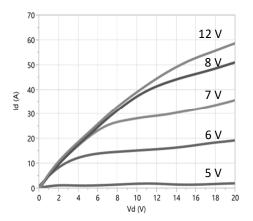


Figure 2. Typical Output Characteristics T_J=150°C

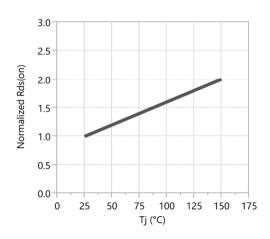


Figure 4. Normalized On-resistance

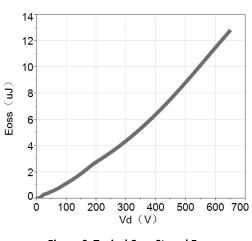
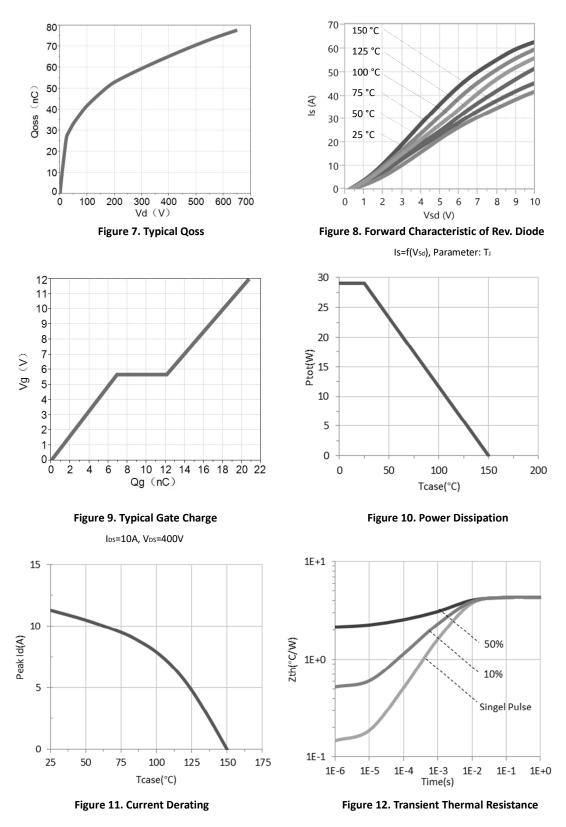


Figure 6. Typical Coss Stored Energy

5 / 10 This datasheet is subject to change without notice.



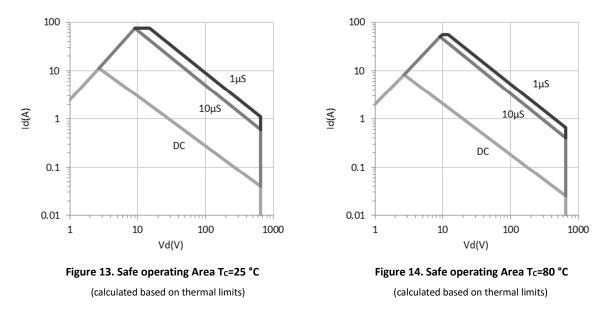
Typical Characteristics, at Tc=25 °C, unless otherwise specified





RX65T125FS2A

Typical Characteristics, at Tc=25 °C, unless otherwise specified





Test Circuits and Waveforms

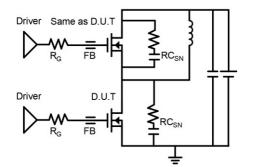


Figure 15. Switching Time Test Circuit

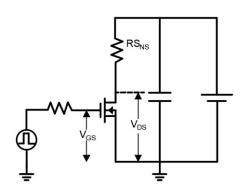


Figure 17. Dynamic RDS(on) Test Circuit

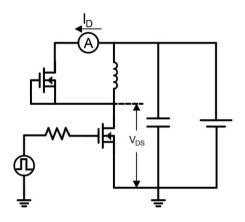


Figure 19. Diode Characteristic Test Circuit

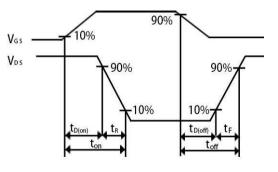


Figure 16. Switching Time Waveform

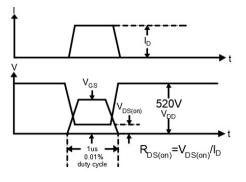


Figure 18. Dynamic R_{DS(on)} Waveform

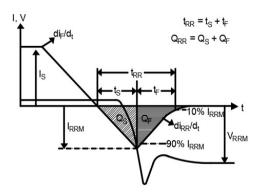


Figure 20. Diode Recovery Waveform



Design Considerations

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

Before evaluating Runxin Micro's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

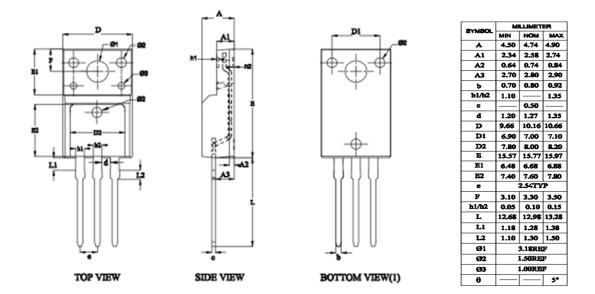
DO	DO NOT
Make sure the traces are as short as possible for both	Using Runxin Micro's devices in GDS board layouts
drive and power loops to minimize parasitic inductance	
Use the test tool with the shortest inductive loop, and	Use differential mode probe or probe ground clip with
make sure test points should be placed close enough	long wires
Minimize the lead length of TO packages when	Use long traces in drive circuit, or long lead length of
installing them to PCB	the devices

When Evaluating Runxin Micro's GaN Devices:



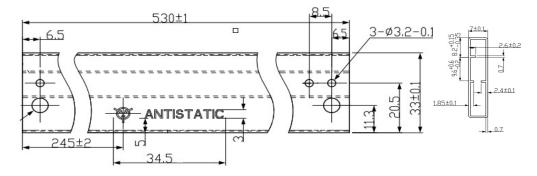
Package Outline

Pin 1: Gate; Pin 2: Source; Pin 3: Drain



Tube Information

Dimensions are shown in millimeters



Revision History

Version	Date	Change(s)	
0.1	04/10/2023	Release formal datasheet	